

<b>Notice of References Cited</b>	Application/Control No. 10/092,887	Applicant(s)/Patent Under Reexamination BRANDES ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-US005425860A	06-1995	Truher et al.	204/192.23
	C	US-4109271 A	08-1978	Pankove	257/53
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	E	US-US005831324A	11-1998	Bang	257/508
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**NON-PATENT DOCUMENTS**

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	U	Gail Dewey, "Morton Announces Low Resistivity Components for Semiconductor Manufacturing", 18 June 1999, Rohm and Haas Co. Press Release and CVD Silicon Carbide Data Sheet.
	V	Nagai et al., "SiC Thin Film Thermistor", Thin Solid Films, Vol. 125, (October 11, 1984), pp. 355-359.
	W	Wahab et al., "Growth of epitaxial 3C-SiC films on (111) silicon substrates at 850 deg C by reactive magnetron sputtering", Journal of Applied Physics, Vol. 74, Issue 3, (August 1, 1993), pp. 1663-1669.
	X	Kortright et al., "Amorphous silicon carbide coatings for extreme ultraviolet optics", 15 July 1988, Applied Optics, Vol. 27, No. 14, pp. 2841-2846.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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